

REMARKS

An interview between Examiner Olsen and Dennis Smid (one of the applicants' undersigned attorneys) was held on March 7, 2007. The applicants and Mr. Smid wish to thank the Examiner for his time and consideration for such interview.

Claims 1, 3, and 6-8 have been canceled. Claim 5, amended claims 2 and 4, and new claims 9-11 are in this application.

Claims 2, 4, and 5 were rejected under 35 U.S.C. 112, second paragraph. In explaining this 112 rejection, the Examiner stated that the word "arranged" in claim 4 is "not fully understood." As discussed during the March 7 interview, claim 4 has been amended herein so as to change the word "arranged" to "formed." As such, it is respectfully requested that this 112 rejection be withdrawn.

Claims 2 and 4 were rejected under 35 U.S.C. 102(b) as being anticipated by U.S. Patent 4,985,116 to Mettler et al. Claims 2 and 4 were rejected under 35 U.S.C. 102(b) as being anticipated by JP 07-319146.

Amended independent claim 4 recites in part the following:

"A method for decorating a surface of a die .
. .

wherein said pattern is formed on a surface
of the photomask uniformly." (Emphasis
added.)

It is respectfully submitted that neither Mettler nor JP 07-319146 as applied by the Examiner disclose the above features of claim 4. That is, the portions of Mettler and JP

07-319146 relied on by the Examiner do not appear specifically disclose or relate to a "method for decorating a surface of a die" in which a "pattern is formed on a surface of the photomask uniformly" as specifically set forth in claim 4. As discussed during the March 7 interview, such die may be usable with a molding process to form a three-dimensional object such as a diaphragm for a speaker having a uniform pattern formed thereon. Mettler and JP 07-319146, on the other hand, appear to describe techniques for forming wiring or circuit patterns onto a part or substrate and do not appear to disclose a technique for decorating a surface of a die so that the molded object has a uniform pattern formed thereon.

Claim 2 is dependent from independent claim 4. Accordingly, it is also respectfully submitted that dependent claim 2 is distinguishable from either Mettler or JP 07-319146 as applied by the Examiner for at least the reasons previously described.

Claim 5 was rejected under 35 U.S.C. 103(a) as being unpatentable over Mettler.

Claim 5 is dependent from independent claim 4. Accordingly, it is also respectfully submitted that dependent claim 5 is distinguishable from Mettler as applied by the Examiner for at least the reasons previously described.

New independent claim 11 and new dependent claims 9 and 10 have been added herein.

New claims 9 and 10 are dependent from independent claim 4. Accordingly, it is also respectfully submitted that dependent claims 9 and 10 are distinguishable from either Mettler or JP 07-319146 as applied by the Examiner for at least the reasons previously described.

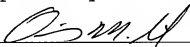
New independent claim 11 includes features discussed during the March 7 interview. As discussed during the March 7 interview, it is respectfully submitted that new claim 11 is distinguishable from either Mettler or JP 07-319146 as applied by the Examiner.

As it is believed that all of the rejections set forth in the Official Action have been overcome, favorable reconsideration and allowance are earnestly solicited. If, however, for any reason the Examiner does not believe that such action can be taken at this time, it is respectfully requested that the Examiner telephone applicants' attorney at (908) 654-5000 in order to overcome any additional objections and/or rejections which the Examiner might have.

If there are any charges in connection with this requested amendment, the Examiner is authorized to charge Deposit Account No. 12-1095 therefor.

Dated: April 4, 2007

Respectfully submitted,

By 
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